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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination OH ET AL. | |
| | | 10/663,023 | Examiner Alix Elizabeth Echelmeyer | |
| | | | Art Unit 1745 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------|----------------|
| * | A | US-6,858,351 | 02-2005 | Miura et al. | 429/317 |
| * | B | US-2004/0197665 | 10-2004 | Amine et al. | 429/313 |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | E | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | . | | |
| | K | US- | . | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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